Search Notes

Application/Control No.	o. Applicant(s)/Patent under Reexamination	
10/812,972	NIEN ET AL.	
Examiner	Art Unit	
Eric Chang	2116	

SEARCHED					
Class	Subclass	Date	Examiner		
713	320	9/8/2006	EC		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST USPAT/PGPUB EPO/JPO	9/8/2006	EC